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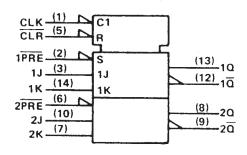
- Package Options Include Plastic "Small Outline" Packages, Flat Packages, and Plastic and Ceramic DIPs
- Dependable Texas Instrument Quality and Reliability

description

The 'LS78A contains two negative-edge-triggered flipflops with individual J-K, preset inputs, and common clock and common clear inputs. The logic levels at the J and k inputs may be allowed to change while the clock pulse is high and the flip-flop will perform according to the function talbe as long as minimum setup and hold times are observed. The preset and clear are asynchronous active-low inputs. When low they override the clock and data inputs forcing the outputs to the steady-state levels as shown in the function table.

The SN54LS78A is characterized for operation over the full military temperature range of -55 °C to 125 °C. The SN74LS78A is characterized for operation from 0 °C to 70 °C.

logic symbol[†]



[†]This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12.

SN54LS78A . . . J OR W PACKAGE SN74LS78A . . . D OR N PACKAGE (TOP VIEW)

CLK []1 J14∏1K 1 PRE 2 13 110 1J 🛛 3 12 10 11 GND Vcc[4 CLR 15 10 2J 2 PRE 6 9**∏**2<u>0</u> 2K 8 20



	IN	OUTPUTS					
PRE CLR CL		CLK	JK		٥	ā	
L	н	Х	Х	X	Н	L	
н	٤	х	Х	X	L	н	
L	L	х	х	X	H‡	н‡	
н	н	Ļ	L	L	00	$\overline{\alpha}_0$	
н	н	t.	Н	L	н	L	
н	н	ŧ	L	н	L	н	
н	н	\$	Н	н	TOGGLE		
н	H	н	Х	х	۵ ₀	āo	

[‡]This configuration is nonstable; that is, it will not persist when preset and clear inputs return to their inactive (high) level.

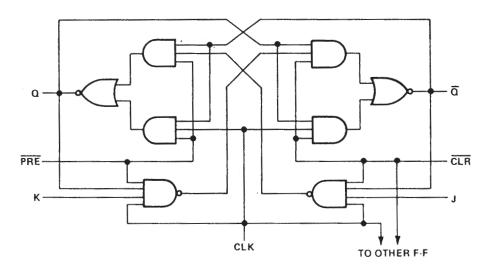
PRODUCTION DATA information is current as of publication date. Products conform to specifications per the terms of Texas Instruments standard warranty. Production processing does not necessarily include testing of all parameters.



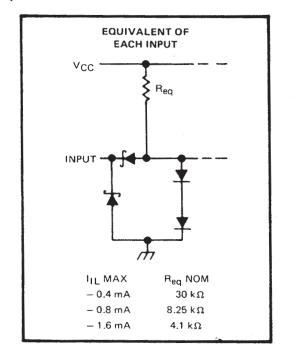
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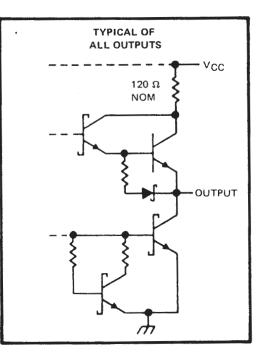
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logic diagram (positive logic)



schematics of inputs and outputs (continued)





absolute maximum ratings over operating free-air temperature range (unless otherwise noted)

Supply voltage, V _{CC} (see Note 1)	
Input voltage	
Operating free-air temperature range: SN54LS78A	- 55°C to 125°C
SN74LS78A	0°C to 70°C
Storage temperature range	65°C to 150°C

NOTE 1: Voltage values are with respect to network ground terminal.



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recommended operating conditions

			SN54LS78A			SN74LS78A				
			MIN	NOM	MAX	MIN	NOM	MAX	UNIT	
Vcc	Supply voltage		4.5	5	5.5	4.75	5	5.75	V	
VIH	High-level input voltage		2			2			V	
VIL	Low-level input voltage				0.7			0.8	V	
ЮН	High-level output current				- 0.4			- 0.4	mA	
IOL	Low-level output current				4			8	mA	
fclock	Clock frequency	· · · · · · · · · · · · · · · · · · ·	0		30	0		30	MHz	
+	Pulse duration	CLK high	20			20				
tw		PRE or CLR low	25			25			ns	
+	Setup time before CLK 4	data high or low	20			20				
t _{su}	PRE or CLR inact		20			20			ns	
^t h	Hold time-data after CLK+		0			0			ns	
TA	Operating free-air temperature		- 55		125	0		70	°C	

electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER		TEST CONDITIONS [†]		S	SN54LS78A			SN74LS78A			
		TEST CONDITIONS			MIN	TYP‡	MAX	MIN	TYP‡	‡ MAX	UNIT
VIK		V _{CC} = MIN,	lı = - 18 mA				- 1.5			- 1.5	V
Vон		V _{CC} = MIN,	V _{IH} = 2 V,	V _{IL} = 0.7 V,							
		IOH = - 0.4 mA			. 2.5	3.4					
		$V_{CC} = MIN,$	V _{IH} = 2 V,	V _{IL} = 0.8 V,				0.7	2.4		V
		I _{OH} = - 0.4 mA						2.7	3.4		
		V _{CC} = MIN,		V _{IH} = 2 V,		0.05	0.4		0.05	0.4	
VOL		IOL = 4 mA				0.25	0.4		0.25	0.4	v
VUL		V _{CC} = MIN,	VIL = MAX,	V _{IH} = 2 V,					0.35	0.5	v
		10L = 8 mA							0.35	0.5	
	J or K						0.1			0.1	
4	CLR	V _{CC} = MAX,					0.6			0.6	mA
-1	PRE		•1-1•				0.3			0.3	
	CLK						0.8			0.8	
	J or K	V _{CC} = MAX,	V ₁ = 2.7 V				20			20	
ЧΗ	CLR						120			120	μA
	PRE						60			60	# ^
	CLK						160			160	
	J or K	V _{CC} = MAX,	$V_{L} = 0.4 V_{L}$				- 0.4			- 0.4	
ιL	CLR						- 1.6			- 1.6	mA
	PRE		1 0.4 0				- 0.8			- 0.8	
	CLK						- 1.6			- 1.6	
los§		V _{CC} = MAX,	See Note 4		- 20		- 100	- 20		- 100	mA
ICC (To	otal)	$V_{CC} = MAX,$	See Note 2			4	6		4	6	mA

† For conditions shown as MIN or MAX, use the appropriate value specified under recommended operating conditions.

[‡] All typical values are at $V_{CC} = 5 V$, $T_A = 25^{\circ}C$.

§ Not more than one output should be shorted at a time, and the duration of the short circuit should not exceed one second.

NOTE 2: With all outputs open, I_{CC} is measured with the Q and \overline{Q} outputs high in turn. At the time of measurement, the clock input is grounded.

NOTE 4: For certain devices where state commutation can be caused by shorting an output to ground, an equivalent test may be performed with V_O ≈ 2.25 V and 2.125 V for the 54 family and the 74 family, respectively, with the minimum and maximum limits reduced to one half of their stated values.



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switching characteristics, $V_{CC} = 5 V$, $T_A = 25^{\circ}C$ (see note 3)

PARAMETER	FROM (INPUT)	то (ОUТР́UT)	TEST CONDITIONS		MIN	түр	MAX	UNIT
fmax					30	45		MHz
^t PLH	PRE, CLR or CLK	Q or Q	$R_L = 2 k \Omega$,	CL = 15 pF		15	20	ns
tPHL						15	20	ns

NOTE 3: Load circuits and voltage waveforms are shown in Section 1.



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